MOSFET - Power, Single, N-Channel, DPAK/IPAK 30 V, 40 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low RG
- NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters
- High Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

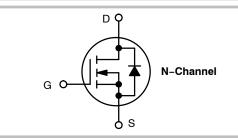
Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Vol	tage		V_{GS}	±20	V
Continuous Drain Current Raja		T _A = 25°C	Ι _D	9.0	Α
(Note 1)		T _A = 85°C		7.0	
Power Dissipation R ₀ JA (Note 1)		T _A = 25°C	P _D	1.94	W
Continuous Drain Current R _{0.IA}	1	T _A = 25°C	ID	7.6	Α
(Note 2)	Steady State	T _A = 85°C		5.9	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	1.27	W
Continuous Drain Current R _{BJC}		T _C = 25°C	I _D	40	Α
(Note 1)		T _C = 85°C		31	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	35.3	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	90	Α
Current Limited by Package $T_A = 25^{\circ}C$			I _{DmaxPkg}	35	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	–55 to +175	°C
Source Current (Body Diode)			I _S	29	Α
Drain to Source dV/dt			dV/dt	6	V/ns



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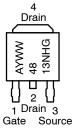
V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	13 mΩ @ 10 V	40.4
30 V	25.9 mΩ @ 4.5 V	40 A





DPAK CASE 369AA (Bent Lead) STYLE 2

MARKING DIAGRAM & PIN ASSIGNMENT



A = Assembly Location*

Y = Year WW = Work Week 4813NH = Device Code G = Pb-Free Package

* The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

ORDERING INFORMATION

See detailed ordering and shipping information on page 7 of this data sheet.

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Value	Unit
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 24 V, V_{GS} = 10 V, I_L = 17.2 A_{pk} , L = 0.3 mH, R_G = 25 Ω)	EAS	44.4	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.25	
Junction-to-TAB (Drain)	$R_{ heta JC-TAB}$	3.5	°C/M/
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	77.5	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	118.5	

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

FLECTRICAL CHARACTERISTICS (T.

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	<u>. </u>				1	I	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				24.5		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	۸
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		10.9	13	
		11.5 V	I _D = 15 A		10.7		1
		V _{GS} = 4.5 V	I _D = 30 A		20.9	25.9	mΩ
			I _D = 15 A		18.5		
Forward Transconductance	9 _{FS}	V _{DS} = 15 V, I _D = 10 A			6.7		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				940		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 12 V			201		pF
Reverse Transfer Capacitance	C _{RSS}				115		1
Total Gate Charge	Q _{G(TOT)}				7.1	10	
Threshold Gate Charge	Q _{G(TH)}				1.6		1 _
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			3.4		nC
Gate-to-Drain Charge	Q_{GD}				3.0		
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 11.5 V, V_{DS} = 15 V; I_D = 30 A			18.2		nC
SWITCHING CHARACTERISTICS (Note	4)			-	-	<u>-</u>	-
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			10		
Rise Time	t _r				19.5		
Turn-Off Delay Time	t _{d(OFF)}				10.3		ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

4. Switching characteristics are independent of operating junction temperatures.

2.9

Fall Time

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified) (continued)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	lote 4)						
Turn-On Delay Time	t _{d(ON)}				5.1		
Rise Time	t _r	V _{GS} = 11.5 V, V _Γ	_{os} = 15 V,		16.1		ns
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 11.5 \text{ V, } V_{D}$ $I_{D} = 15 \text{ A, } R_{G} = 10.0 \text{ A}$	= 3.0 Ω		17.2		
Fall Time	t _f				1.8		1 !
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 \text{ V}.$ $T_J = 25^{\circ}\text{C}$			0.95	1.2	
		$V_{GS} = 0 \text{ V},$ $I_S = 30 \text{ A}$ $I_J = 25^{\circ}\text{C}$ $I_J = 125^{\circ}\text{C}$		0.9		V	
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dls/dt = 100 A/μs, l _S = 30 A			15		
Charge Time	t _a				9.9		ns
Discharge Time	t _b				5.1		
Reverse Recovery Charge	Q _{RR}				7.0		nC
PACKAGE PARASITIC VALUES	-						
Source Inductance	L _S	T _A = 25°C			2.49		nH
Drain Inductance, DPAK	L _D				0.0164		
Drain Inductance, IPAK	L _D				1.88		
Gate Inductance	L _G				3.46		
Gate Resistance	R _G				0.55		Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

4. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

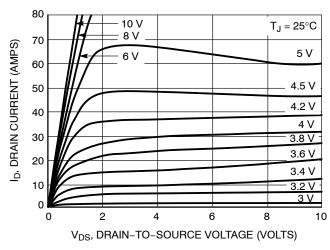
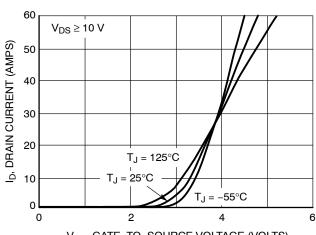


Figure 1. On-Region Characteristics



V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 2. Transfer Characteristics

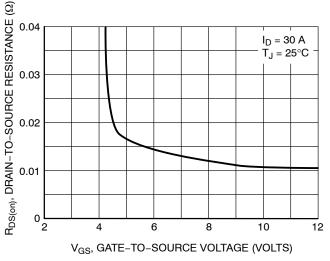


Figure 3. On-Resistance vs. Gate-to-Source Voltage

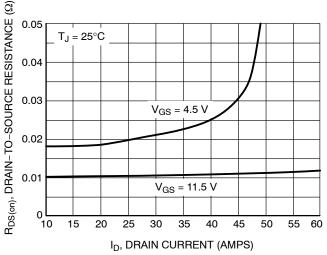


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

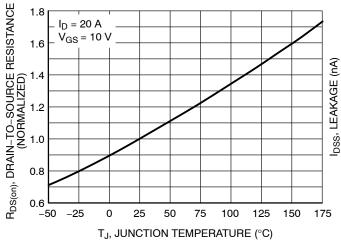


Figure 5. On–Resistance Variation with Temperature

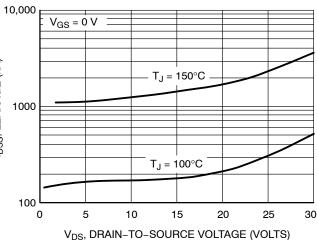


Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES

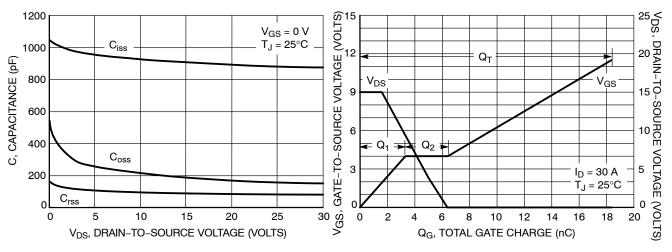


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

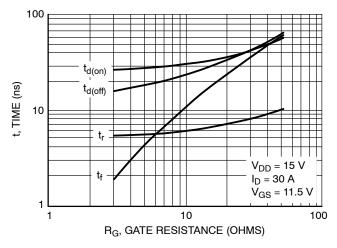


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

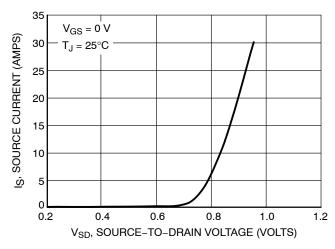


Figure 10. Diode Forward Voltage vs. Current

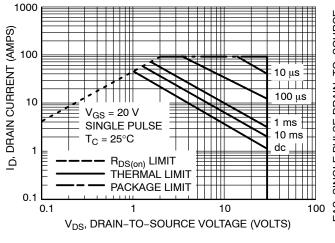


Figure 11. Maximum Rated Forward Biased Safe Operating Area

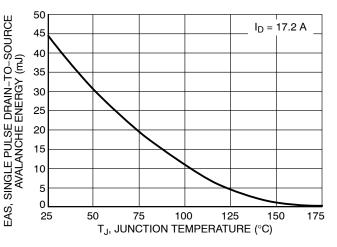


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

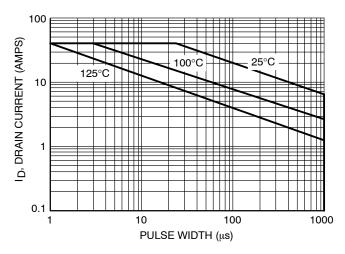


Figure 13. Avalanche Characteristics

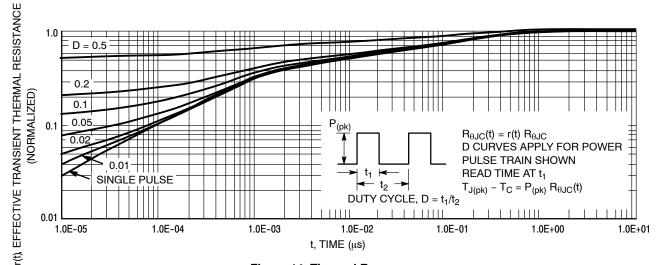


Figure 14. Thermal Response

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD4813NHT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NVD4813NHT4G*	DPAK (Pb-Free)	2500 / Tape & Reel

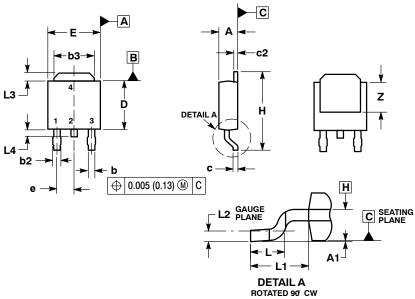
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA ISSUE B



NOTES:

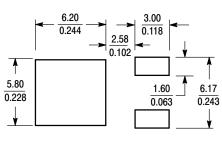
- 1. DIMENSIONING AND TOLERANCING PER ASME Y14 5M 1994
- Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES
- 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- MENSIONS DAND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIM	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	0.090 BSC		BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108 REF		2.74 REF		
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

DRAIN

SOLDERING FOOTPRINT*



SCALE 3:1 $\left(\frac{\text{mm}}{\text{inches}}\right)$

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.